



BSI Standards Publication

Semiconductor devices - Mechanical and climatic test methods

Part 4: Damp heat, steady state, highly accelerated stress test (HAST) (IEC 60749-4:2017)

National foreword

This British Standard is the UK implementation of EN 60749-4:2017. It is identical to IEC 60749-4:2017. It supersedes BS EN 60749-4:2002, which is withdrawn.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

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